9 CLK

- Four J-K Flip-Flops in a Single Package . . . Can Reduce FF Package Count by 50%
- Common Positive-Edge-Triggered Clocks with Hysteresis . . . Typically 200 mV
- Fully Buffered Outputs
- Typical Clock Input Frequency . . . 45 MHz

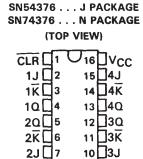
description

These quadruple TTL J-K flip-flops incorporate a number of third-generation IC features that can simplify system design and reduce flip-flop package count by as much as 50%. They feature hysteresis at the clock input, fully buffered outputs, and direct clear capability. The positive-edge-triggered SN54376 and SN74376 are directly compatible with most Series 54/74 MSI registers.

The SN54376 is characterized for operation over the full military temperature range of -55°C to 125°C; the SN74376 is characterized for operation from 0°C to 70°C.

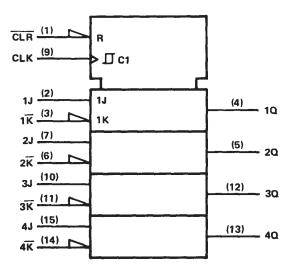
FUNCTION TABLE (EACH FLIP-FLOP)

COMMON INPUTS		INP	UTS	OUTPUT		
CLEAR	CLOCK	J	ĸ	a		
L	Х	X	Х	L		
н	†	L	Н	σ_0		
н	†	Н	Н	н		
н	†	L	L	L		
н	†	.н	L	TOGGLE		
Н	L	×	X	α ₀		



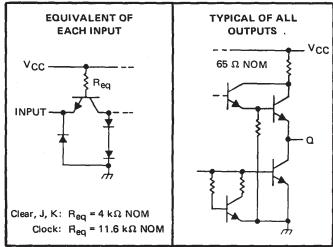
GND □8

logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

schematics of inputs and outputs



Resistor values shown are nominal.

TEXAS INSTRUMENTS

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)		,
Input voltage	5.5 V	1
Operating free-air temperature range:	SN5437655°C to 125°C	,
operating mee an emperation anger	SN74376 0 °C to 70 °C	,
	65°C to 150°C	

NOTE 1: Voltage values are with respect to network ground terminals.

recommended operating conditions

		SN54376		SN74376			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}		4.5	5	5.5	4.75	5	5.25	V
High-level output current, IOH				-800			-800	μΑ
Low-level output current, IOL				16			16	mA
Clock frequency		0		30	0		30	MHz
Pulse width, t _W	Clock high	22			22			
	Clock low	12			12			ns
	Preset or clear low	12			12			
Setup time, t _{su}	J, K inputs	01			01			ns
	Clear inactive state	10↑			10↑			113
Input hold time, th		201			201			ns
Operating free-air temperature, TA		- 55		125	0		70	°c

^{↑↓}The arrow indicates the edge of the clock pulse used for reference: ↑ for the rising edge, ↓ for the falling edge,

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		MIN	TYP‡	MAX	UNIT
VIH	High-level input voltage			2			V
VIL	Low-level input voltage					8.0	V
VIK	Input clamp voltage	V _{CC} = MIN,	I _I = -12 mA			-1.5	V
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IL} = 0.8 V,	V _{1H} = 2 V, I _{OH} = -800 μA	2.4	3,4		V
VOL	Low-level output voltage	V _{CC} = MIN, V _{IL} = 0.8 V,	V _{IH} = 2 V, I _{OL} = 16 mA		0.2	0.4	V
I _I	Input current at maximum input voltage	VCC = MAX,	V _I = 5.5 V			1	mA
Тін	High-level input current	V _{CC} = MAX,	V _I = 2.4 V			40	μΑ
TIL	Low-level input current	V _{CC} = MAX,	V ₁ = 0.4 V			-1.6	mA
los	Short-circuit output current§	V _{CC} = MAX		-30		-85	mA
ICC	Supply current	V _{CC} = MAX			52	74	mA

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
f _{max}	Maximum clock frequency	C 15 pF	30	45		MHz
tPHL	Propagation delay time, high-to-low-level output from clear	$C_L = 15 pF$, $R_L = 400 \Omega$,		17	30	ns
tPLH	Propagation delay time, low-to-high-level output from clock	See Note 2		22	35	ns
tPHL	Propagation delay time, high-to-low-level output from clock	366 IAO(6.2		24	35	ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



 $^{^{\}ddagger}$ Ail typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}$ C.

[§]Not more than one output should be shorted at a time.

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